

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/453,934	MOTOYAMA ET AL.		
Examiner	Art Unit		
Nabil M. El-Hady	2154		

	SEARCHED					
Class	Subclass	Date	Examiner			
709	203					
	217					
	219	2/12/02				
	224					
	229					
	232		•			
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INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				
Same	As Sear	Jud S/p/	-NE				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
		DATE	EXMR		
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NPL (IEEE)					
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